ONEIDA RESEARCH SERVICES, INC.	Component Analysis Submission Form					
	Client: Date:					
	Company: P.O. No.:					
INSPECTION • ANALYSIS • TESTING 8282 Halsey Road, Building 1 Whitesboro, NY 13492 1 (855) ORS-LABS Attn: Component Testing Group E-mail: component@orslabs.com	Address: Rel No.:					
	Tel:					
	E-mail: Fax:					
	ORS Quote No.:					
Package Type(s):	# of Samples: Will samples be used for Flight production (lot screening)?					
Do samples be used for Fight production (for screening)?						
ANALYSIS REQUESTED						
(Discussion of analysis is recommended	prior to quotation and submission)					
Destructive Physical Mil-Std:	Failure Analysis Construction Analysis					
Analysis (DPA) per Mil-Std or Customer Test Method:	(Consultation required prior to analysis)					
Specification Client SOW:	Surface/Material Analysis Other					
METHODS OF ANALYSIS						
🔲 Internal Vapor Analysis (IVA®, H						
Radioisotope Leak Testing (Kr						
Combined He/O ₂ Dry Gross and F	-ine Leak (HSHLD°) [*] ☐ Borid Puil ☐ Die Shear [*]					
	Plasma/Chemical I.C. Deprocessing					
	·					
☐ Field Emission SEM (FeSEM)	Cross-Sectional Analysis					
Scanning Electron Microscopy						
Energy Dispersive X-ray Spect						
Micro Fourier Infrared Spectro						
	Thermal Cycling					
X-Ray Fluorescence (XRF)	Consulting Services					
Real Time X-ray Radiography*	PEM Laser/Acid De-Encapsulation					
Leak Site Identification	Other:					
Dye Impregnation/Penetrant	Dye Impregnation/Penetrant					
*Analysis performed to DLA approved test methods must be included in the ORS retention log to DLA Land and Maritime as part of the Laboratory Suitability program.						
Request phone consultation upon	receipt.					
REPORT FORMAT						
Electronic Report (.pdf file format) Original Hard Copy Report Images Only						
Return Shipment Additional Instructions or Restrictions						
UPS: Red Blue Ground Fed Ex: Pr. 1 Std. Econ.						
Other:						
Acct. #:						
Form: LOG-9-F02 IVA [®] , HR-IVA [®] and HSHLD [®] are registered trademarks of Oneida Research Services, Inc.						
Revision 3 See reverse side for additional information						

DESCRIPTION OF TEST METHODS

	Condition	Method	Mil-Std 883 Test
In	A1, A2, A5, B1, B2, B1/B2 and B3	1014	Seal
	N/A	2009	External Visual
[A, B	2010	Internal Visual (Monolithic)
Bond	Non-Film (Digital)	2012	Radiography
	N/A	2016	Physical Dimensions
P	H and K	2017	Internal Visual (Hybrid)
PR	N/A	2018	SEM
	A, B	2020	PIND
Vis	N/A	1018	Internal Gas Analysis
Inte	Condition D	2011	Bond Strength
(P	N/A	2019	Die Shear
Vis	H and K	2032	Internal Visual (Passive)
l (se			

ORS APPROVED DLA LAND AND MARITIME SUITABLE TEST METHODS

Mil-Std 750 Test	Method	Condition
Internal Gas Analysis	1018	N/A
Seal	1071	A, B, G1, G2, H1, H2, H3
Die Attach Integrity	2017	Condition A
Bond Strength (Destructive Bond Pull)	2037	Condition D
Physical dimensions	2066	
PRE-CAP visual, power MOSFET'S	2069	
Visual and mechanical examination	2071	
Internal Visual transistor (PRE-CAP) inspection	2072	
Visual inspection for die (semiconductor diode)	2073	
DECAP Internal Visual Design Verification	2075	
Radiography	2076	Non-Film (Digital)
SEM	2077	N/A
PIND	2052	A, B
Destructive Physical Analysis for wire bonded devices	2102	

These test procedures are used exclusively for testing of devices in accordance with current versions of Mil-Std 883 and Mil-Std 750 per the conditions of "Suitability" status granted by DLA Land and Maritime. No variations are permitted to the procedure nor to the device test conditions. Furthermore, all tests performed are subject to inclusion in ORS' annual retention report submitted to DLA Land and Maritime. All records regarding these tests are subject to audit and inspection by the U.S. Government.

SOME IMPORTANT REMINDERS

- Please provide a valid Purchase Order and, if requested by your company, a Release Number.
- Please be sure to specify "Additional Instructions or Restrictions" that should be followed during sample handling, testing or shipment.
- Unless otherwise requested, test reports will be sent electronically and samples will be returned via UPS Ground.
- Devices subjected to Radioisotope Hermetic Seal testing may be retained by ORS until suitable background levels are achieved before devices may be returned to the client.
- Please refer to the ORS terms and conditions of Quotation and Sale at www.orslabs.com/terms-conditions-sale.

- All shipping and handling fees associated with the transportation of samples to and from our testing facility, as well as special courier fees for expediting test reports, are the responsibility of the client.
- On-site visits are encouraged and we welcome your personal involvement during sample analysis.
- Please contact our Sales Department for pricing information.
- For technical information, please contact the Component Testing Group at (855) ORS-LABS.